

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	592	(compact\$1 or compress\$3 or "XOR gate\$1" or logic gate\$1) same (scan chain\$1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:33
L3	175261	("Exclusive OR matrix" or "Exclusive OR gate\$1" or "Exclusive OR\$3" or "ExOR matrix") or ("exclusive ORing" or "XOR\$4" or "ExOR\$4") or (logic circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:34
L4	11978	scan path\$1 or scan logic or scan chain\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:34
L5	1543	linear matrix or linear-matrix	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:34
L6	372335	flip-flop\$1 or FF	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:35

L7	2299440	pin\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:35
L8	15282	714/718,724,726,727,729,738,30,733,734;716/4.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:37
L9	1	l2 and l5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:40
L10	89721	l6 and l7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42
L11	1890	l10 and l4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42
L12	1	l11 and l5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42

L13	225	l11 and l2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42
L14	97	l13 and l3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42
L15	69	l14 and l8	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:42
L16	1799381	integrated circuit or IC	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:44
L17	63	l15 and l16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:45
L18	1	test compaction same Linear-Matrix same scan chain\$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:47

L19	1544	"ATPG" or automatic test pattern generator	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:48
L20	37	I17 and I19	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/06/27 15:48

6/27/08 4:18:12 PM

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